# **Quad Bus Buffer**

# with 3-State Control Inputs

The NLSF3T125 is a high speed CMOS quad bus buffer fabricated with silicon gate CMOS technology. It achieves high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

The NLSF3T125 requires the 3–state control input  $(\overline{OE})$  to be set High to place the output into the high impedance state.

The T125 inputs are compatible with TTL levels. This device can be used as a level converter for interfacing 3.3 V to 5.0 V, because it has full 5.0 V CMOS level output swings.

The NLSF3T125 input structures provide protection when voltages between 0 V and 5.5 V are applied, regardless of the supply voltage. The output structures also provide protection when  $V_{CC}=0$  V. These input and output structures help prevent device destruction caused by supply voltage – input/output voltage mismatch, battery backup, hot insertion, etc.

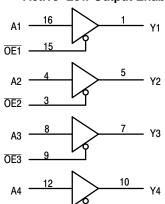
The internal circuit is composed of three stages, including a buffer output which provides high noise immunity and stable output. The inputs tolerate voltages up to 7.0 V, allowing the interface of 5.0 V systems to 3.0 V systems.

- High Speed:  $t_{PD} = 3.8 \text{ ns}$  (Typ) at  $V_{CC} = 5.0 \text{ V}$
- Low Power Dissipation:  $I_{CC} = 4.0 \,\mu\text{A}$  (Max) at  $T_A = 25^{\circ}\text{C}$
- TTL-Compatible Inputs:  $V_{IL} = 0.8 \text{ V}$ ;  $V_{IH} = 2.0 \text{ V}$
- Power Down Protection Provided on Inputs
- Balanced Propagation Delays
- Designed for 2.0 V to 5.5 V Operating Range
- Low Noise:  $V_{OLP} = 0.8 \text{ V (Max)}$
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 300 mA
- ESD Performance: Human Body Model; > 2000 V,

Machine Model; > 200 V

• Chip Complexity: 72 FETs or 18 Equivalent Gates

### **Active-Low Output Enables**



FUNCTION TABLE

	NLSF3T125							
	Inj	outs	Output					
	Α	OE	Υ					
	Н	L	Н					
	L	L	L					
L	Χ	Н	Z					

Figure 1. Logic Diagram



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QFN-16 CASE 485G

### MARKING DIAGRAM



(Top View)

A = Assembly Location

WL = Wafer Lot

Y = Year

WW = Work Week

#### **ORDERING INFORMATION**

Device	Package	Shipping†		
NLSF3T125MNR2	QFN-16	3000 Units/ Tape & Reel		

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

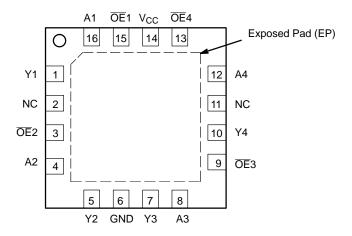


Figure 2. QFN - 16 Pinout (Top View)

### **MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	DC Supply Voltage	- 0.5 to + 7.0	V
V <sub>in</sub>	DC Input Voltage	- 0.5 to + 7.0	V
V <sub>out</sub>	DC Output Voltage Output in 3-State High or Low State	- 0.5 to + 7.0 - 0.5 to V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input Diode Current	- 20	mA
I <sub>OK</sub>	Output Diode Current (V <sub>OUT</sub> < GND; V <sub>OUT</sub> > V <sub>CC</sub> )	± 20	mA
l <sub>out</sub>	DC Output Current, per Pin	± 25	mA
I <sub>CC</sub>	DC Supply Current, V <sub>CC</sub> and GND Pins	± 75	mA
P <sub>D</sub>	Power Dissipation in Still Air, QFN Packages	500	mW
T <sub>stq</sub>	Storage Temperature	- 65 to + 150	°C

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high–impedance circuit. For proper operation,  $V_{in}$  and  $V_{out}$  should be constrained to the range GND  $\leq$  ( $V_{in}$  or  $V_{out}$ )  $\leq$   $V_{CC}$ .

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or  $V_{CC}$ ). Unused outputs must be left open.

Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If stress limits are exceeded device functional operation is not implied, damage may occur and reliability may be affected. Functional operation should be restricted to the Recommended Operating Conditions.

### RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	DC Supply Voltage	2.0	5.5	V
V <sub>in</sub>	DC Input Voltage	0	5.5	V
V <sub>out</sub>	DC Output Voltage Output in 3-State High or Low State	0	5.5 V <sub>CC</sub>	V
T <sub>A</sub>	Operating Temperature	- 40	+ 85	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time $V_{CC} = 5.0 \text{ V} \pm 0.5 \text{ V}$	0	20	ns/V

## DC ELECTRICAL CHARACTERISTICS

				v <sub>cc</sub>			T <sub>A</sub> = 25°C		T <sub>A</sub> ≤	85°C	<b>T</b> <sub>A</sub> ≤ 1	125°C	
Symbol	Parameter	Test Conditions	(V)	Min	Тур	Max	Min	Max	Min	Max	Unit		
V <sub>IH</sub>	Minimum High-Level Input Voltage	2.3 V ± 0.3 V 3.3 V ± 0.3 V 5.0 V ± 0.5 V		0.5 V <sub>CC</sub> 0.4 V <sub>CC</sub> 0.44 V <sub>CC</sub>			0.5 V <sub>CC</sub> 0.4 V <sub>CC</sub> 0.44 V <sub>CC</sub>		0.5 V <sub>CC</sub> 0.4 V <sub>CC</sub> 0.44 V <sub>CC</sub>		V		
V <sub>IL</sub>	Maximum Low-Level Input Voltage	2.3 V ± 0.3 V 3.3 V ± 0.3 V 5.0 V ± 0.5 V				0.3 V <sub>CC</sub> 0.18 V <sub>CC</sub> 0.18 V <sub>CC</sub>		0.3 V <sub>CC</sub> 0.18 V <sub>CC</sub> 0.18 V <sub>CC</sub>		0.3 V <sub>CC</sub> 0.18 V <sub>CC</sub> 0.18 V <sub>CC</sub>	V		
V <sub>OH</sub>	Minimum High-Level Output Voltage	$V_{OL}$ @ $I_{OL}$ , 50 mA $V_{IN} = V_{IH}$ or $V_{IL}$ $I_{OH} = -50 \mu A$	2.0 3.0 4.5	1.9 2.9 4.4	2.0 3.0 4.5		1.9 2.9 4.4		1.9 2.9 4.4		V		
	$V_{IN} = V_{IH}$ or $\bar{V}_{IL}$	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OH} = -2.0 \text{ mA}$ $I_{OH} = -4.0 \text{ mA}$ $I_{OH} = -8.0 \text{ mA}$	2.0 3.0 4.5	1.82 2.58 3.94			1.72 2.48 3.80		1.60 2.34 3.66				
V <sub>OL</sub>	Maximum Low-Level Output Voltage	$V_{OL} @ I_{OL}$ , 50 mA $V_{IN} = V_{IH}$ or $V_{IL}$ $I_{OL} = 50 \mu A$	2.0 3.0 4.5		0.0 0.0 0.0	0.1 0.1 0.1		0.1 0.1 0.1		0.1 0.1 0.1	V		
	$V_{IN} = V_{IH}$ or $\bar{V}_{IL}$	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 2.0 \text{ mA}$ $I_{OL} = 4.0 \text{ mA}$ $I_{OL} = 8.0 \text{ mA}$	2.0 3.0 4.5			0.36 0.36 0.36		0.44 0.44 0.44		0.52 0.52 0.52			
I <sub>IN</sub>	Maximum Input Leakage Current	V <sub>IN</sub> = 5.5 V or GND	0 to 5.5			± 0.1		± 1.0		± 1.0	μΑ		
I <sub>CC</sub>	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND	5.5			2.0		20		40	μΑ		
Ісст	Quiescent Supply Current	Input: V <sub>IN</sub> = 3.4 V	5.5			1.35		1.50		1.65	mA		
l <sub>OZ</sub>	Maximum 3-State Leakage Current	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$	5.5			±0.25		±2.5		±2.5	μΑ		
I <sub>OPD</sub>	Output Leakage Current	V <sub>OUT</sub> = 5.5 V	0.0			0.5		5.0		10	μΑ		

## AC ELECTRICAL CHARACTERISTICS (Input $t_f = t_f = 3.0 \text{ ns}$ )

			T <sub>A</sub> = 25°C			<b>T</b> <sub>A</sub> = ≤ 85°C			$T_A \le 125^{\circ}C$	
Symbol	Parameter	Test Conditions	Min	Тур	Max	Min	Max	Min	Max	Unit
t <sub>PLH</sub> ,	Maximum Propagation Delay,	$V_{CC} = 2.3 \pm 0.3 \text{ V}$ $C_L = 15 \text{ pF}$	1.0	14.5	16.9	1.0	18.1	1.0	19.2	ns
t <sub>PHL</sub>	A to Y	$V_{CC} = 3.3 \pm 0.3 \text{ V}$ $C_L = 15 \text{ pF}$ $C_L = 50 \text{ pF}$	1.0 1.0	5.6 8.1	8.0 11.5	1.0 1.0	9.5 13.0	1.0 1.0	12.0 16.0	ns
		$V_{CC} = 5.0 \pm 0.5 \text{ V}$ $C_L = 15 \text{ pF}$ $C_L = 50 \text{ pF}$	1.0 1.0	3.8 5.3	5.5 7.5	1.0 1.0	6.5 8.5	1.0 1.0	8.5 10.5	
t <sub>PZL</sub> ,	Maximum Output	$V_{CC} = 2.3 \pm 0.3 \text{ V}$ $C_L = 15 \text{ pF}$	1.0	14.8	16.2	1.0	17.4	1.0	19.3	ns
t <sub>PZH</sub>	Enable Time, OE to Y	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	1.0 1.0	5.4 7.9	8.0 11.5	1.0 1.0	9.5 13.0	1.0 1.0	11.5 15.0	ns
		$V_{CC} = 5.0 \pm 0.5 \text{ V}$ $C_L = 15 \text{ pF}$ $R_L = 1.0 \text{ k}\Omega$ $C_L = 50 \text{ pF}$	1.0 1.0	3.6 5.1	5.1 7.1	1.0 1.0	6.0 8.0	1.0 1.0	7.5 9.5	
t <sub>PLZ</sub> ,	Maximum Output Disable Time, OE to Y	$V_{CC} = 2.3 \pm 0.3 \text{ V}$ $C_L = 15 \text{ pF}$	1.0	15.4	18.0	1.0	19.8	1.0	22.0	ns
t <sub>PHZ</sub>	Disable Time,OE to Y	$V_{CC} = 3.3 \pm 0.3 \text{ V}$ $C_L = 50 \text{ pF}$ $R_L = 1.0 \text{ k}\Omega$	1.0	9.5	13.2	1.0	15.0	1.0	18.0	ns
		$V_{CC} = 5.0 \pm 0.5 \text{ V}$ $C_L = 50 \text{ pF}$ $R_L = 1.0 \text{ k}\Omega$	1.0	6.1	8.8	1.0	10.0	1.0	12.0	ns
t <sub>OSLH</sub> , t <sub>OSHL</sub>	Output-to-Output Skew	$V_{CC} = 3.3 \pm 0.3 \text{ V}$ $C_L = 50 \text{ pF}$ (Note 1)			1.5		1.5		2.0	ns
		$V_{CC} = 5.0 \pm 0.5 \text{ V}$ $C_L = 50 \text{ pF}$ (Note 1)			1.0		1.0		1.5	
C <sub>in</sub>	Maximum Input Capacitance			4	10		10		10	pF
C <sub>out</sub>	Maximum Three–State Output Capacitance (Output in High Impedance State)			6						pF
	<u> </u>				_		DE°C V	F 0	. 1	

		Typical @ 25°C, V <sub>CC</sub> = 5.0V	
$C_{PD}$	Power Dissipation Capacitance (Note 2)	15	pF

Parameter guaranteed by design. t<sub>OSLH</sub> = |t<sub>PLHm</sub> - t<sub>PLHn</sub>|, t<sub>OSHL</sub> = |t<sub>PHLm</sub> - t<sub>PHLn</sub>|.
 C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: I<sub>CC(OPR)</sub> = C<sub>PD</sub> • V<sub>CC</sub> • f<sub>in</sub> + I<sub>CC</sub>/4 (per buffer). C<sub>PD</sub> is used to determine the no–load dynamic power consumption; P<sub>D</sub> = C<sub>PD</sub> • V<sub>CC</sub><sup>2</sup> • f<sub>in</sub> + I<sub>CC</sub> • V<sub>CC</sub>.

# **NOISE CHARACTERISTICS** (Input $t_r = t_f = 3.0 \text{ ns}$ , $C_L = 50 \text{ pF}$ , $V_{CC} = 5.0 \text{ V}$ )

		T <sub>A</sub> =		
Symbol	Characteristic		Max	Unit
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.8	V
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>		- 0.8	V
V <sub>IHD</sub>	Minimum High Level Dynamic Input Voltage		3.5	V
$V_{ILD}$	Maximum Low Level Dynamic Input Voltage		1.5	V

## **SWITCHING WAVEFORMS**

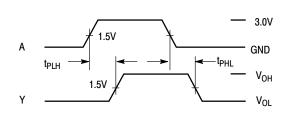


Figure 3.

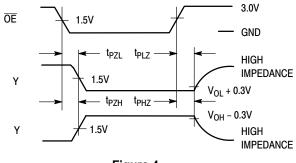
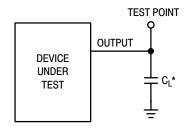
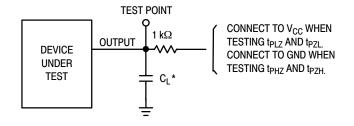


Figure 4.



\*Includes all probe and jig capacitance

Figure 5. Test Circuit

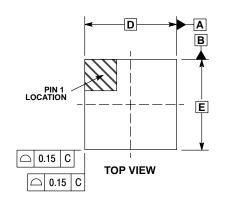


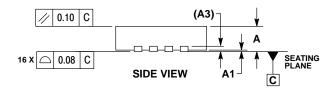
\*Includes all probe and jig capacitance

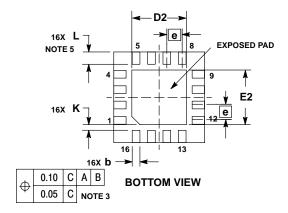
Figure 6. Test Circuit

### **PACKAGE DIMENSIONS**

### 16 PIN QFN CASE 485G-01 ISSUE B







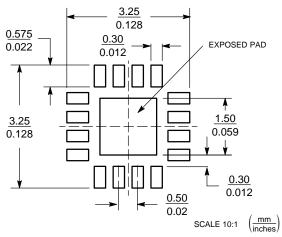
#### NOTES:

- DIMENSIONING AND TOLERANCING PER

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS. DIMENSION & APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM FROM TERMINAL. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.
  Lmax CONDITION CAN NOT VIOLATE 0.2 MM MINIMUM SPACING BETWEEN LEAD TIP AND FLAG AND FLAG

	MILLIMETERS							
DIM	MIN	MAX						
Α	0.80	1.00						
A1	0.00	0.05						
A3	0.20	REF						
b	0.18	0.30						
D	3.00 BSC							
D2	1.65	1.85						
E	3.00	BSC						
E2	1.65	1.85						
е	0.50	BSC						
K	0.20							
L	0.30	0.50						

### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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